

MICROSCOPY TODAY

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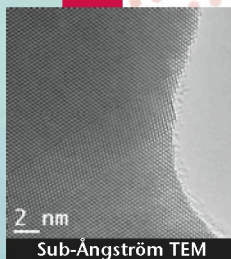
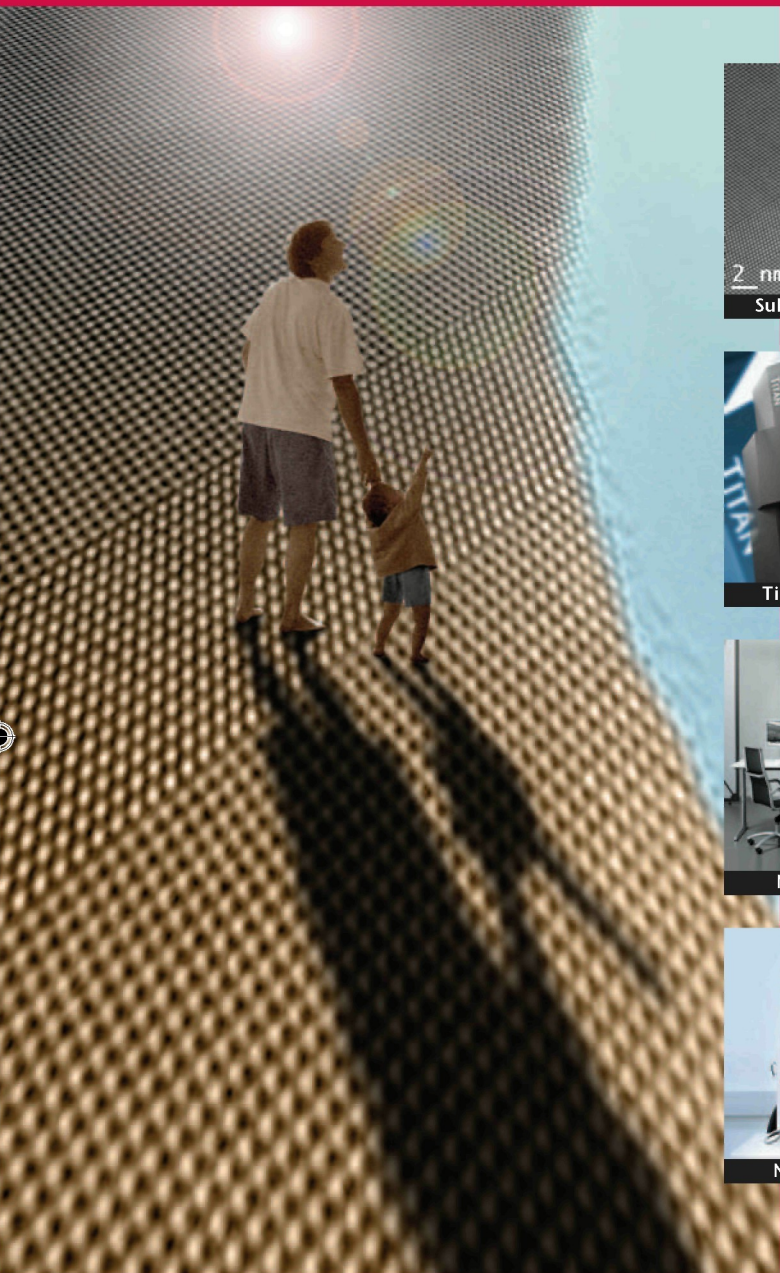


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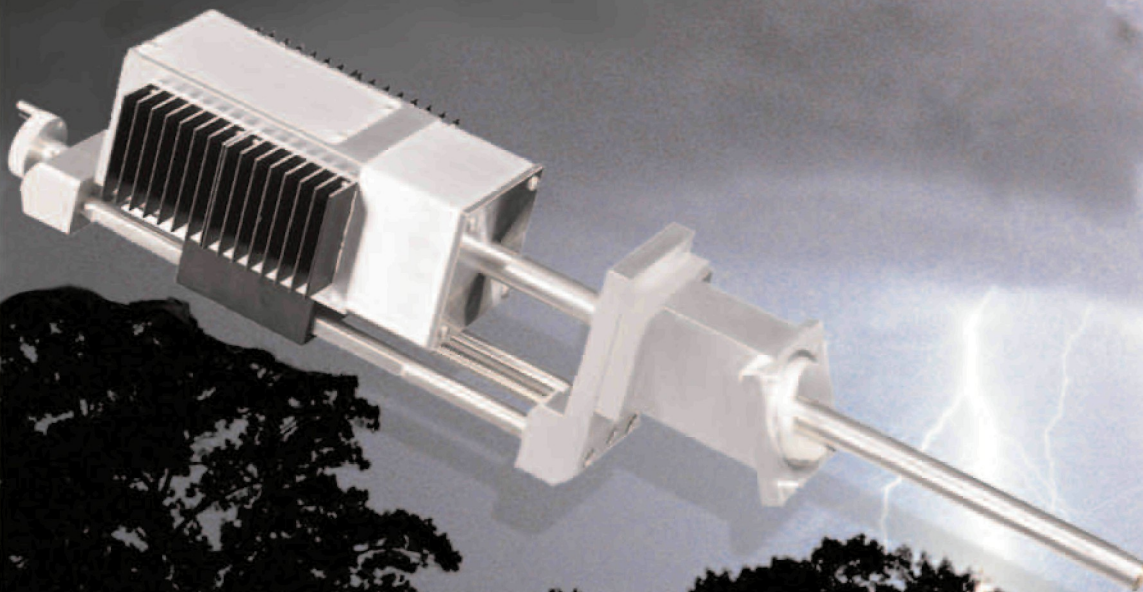
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Polarized Light Microscopy

60: TNT 2,4,6

13:001101

Particle Data:

TNT (2, 4, 6 - Trinitrotoluene), Chemical Abstract Service (CAS) No:118-96-7 is an old, well-known explosive. For this study, two different samples were used, one was an older military sample, possibly mixed with wax, in which form it is often melted, and poured into warheads, and the other was a 99% pure chemical sample (CHEM SERVICE C-2288); no difference in behavior was noted, even though the military sample macroscopically occurred

print save to sample storage

ZOOM 100% BRIGHTNESS

Conditions/Comments

100X
Crossed Polarizers

P60-1 P60-2 P60-3

www.mccroneatlas.com

COMING EVENTS

2005

- ✓ **Microscopy and Microanalysis 2005**
July 31- August 4, 2005, Honolulu, HA
www.msa.microscopy.com
- ✓ **12th Canadian Semiconductor Technology Conference**
August 16 -19, 2005, Ottawa, Ontario, Canada
<http://www.canadiansemiconductor.org>
- ✓ **Advanced Course on Light Microscopy**
September 5-9, 2005, Santa Barbara, CA
www.lifesci.ucsb.edu/mcldb/events/imaging_workshop/index.html
- ✓ **IACEM 2005--8th Inter American Cong. of Electron Microsc.**
September 25-30, 2005, Havana, Cuba
www.ciasem2005.cigb.edu.cu
- ✓ **Scanning Probe Microscopy in Life Sciences**
October 13, 2005, Berlin, Germany
www.spm-workshop.jpk.com
- ✓ **Society for Neuroscience**
November 12-16, 2005, Washington, DC
info@sfn.org
- ✓ **Materials Research Society**
esp: In-Situ Electron Microscopy of Materials, Symposium MM
November 28- December 2, 2005, Boston, MA
info@mrs.org
- ✓ **9th International Symposium on Biomineralization**
December 6-9, 2005, Pucón, Chile
www.cimat.cl/biomin09
- ✓ **American Society for Cell Biology**
December 10-14, 2005, San Francisco, CA
www.ascb.org

2006

- ✓ **PITTCON 2006**
March 12-17, 2006, Orlando, Florida
www.pittcon.org
- ✓ **American Soc. for Biochemistry and Molecular Biology**
April 1-5, 2006, San Francisco, CA
www.asbmb.org
- ✓ **SCANNING 2006**
April 25-27, 2006, Washington, DC
www.scanning-fams.org
- ✓ **Microscopy and Microanalysis 2006**
August 6-10, 2006, Chicago, IL
www.msa.microscopy.com
- ✓ **ICEM XVI International Microscopy Congress**
September 3-8, 2006, Sapporo, Japan
www.imc16.jp
- ✓ **American Society for Cell Biology**
December 9-13, 2006, San Diego, CA
www.ascb.org

2007

- ✓ **Microscopy and Microanalysis 2007**
August 5-9, 2007, Fort Lauderdale, FL
www.msa.microscopy.com

2008

- ✓ **Microscopy and Microanalysis 2008**
August 3-7, 2008, Albuquerque, NM
www.msa.microscopy.com

Please check the "Calendar of Meetings and Courses" in the MSA journal "Microscopy and Microanalysis" for more details and a much larger listing of meetings and courses.

MICROSCOPY TODAY

The objective of this publication is to provide material of interest and value to working microscopists!

The publication is owned by the Microscopy Society of America (MSA) and is produced six times each year in odd months, alternating with MSA's peer-reviewed, scientific journal *Microscopy and Microanalysis*. We greatly appreciate article and material contributions from our readers—"users" as well as manufacturers/suppliers. The only criterion is that the subject matter be of interest to a reasonable number of working microscopists. *Microscopy Today* has authors from many disparate fields in both biological and materials sciences, each field with its own standards. Therefore *MT* does not have a rigid set of style instructions and encourages authors to use their own style, asking only that the writing be clear, informative, and accurate. Length: typical article length is 1,500 to 2,000 words plus images, longer articles will be considered. Short notes are encouraged for our Microscopy 101 section.

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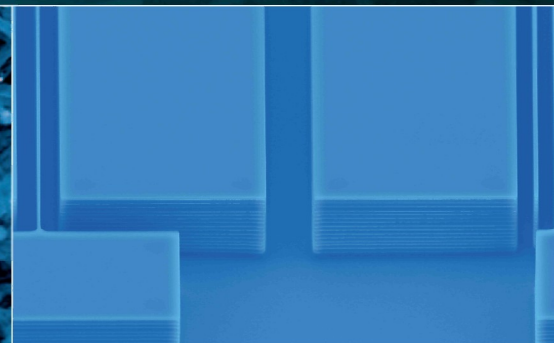
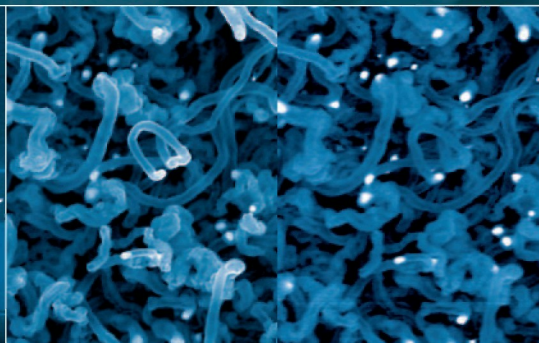
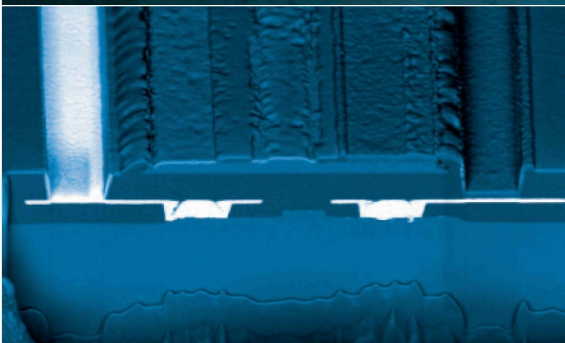
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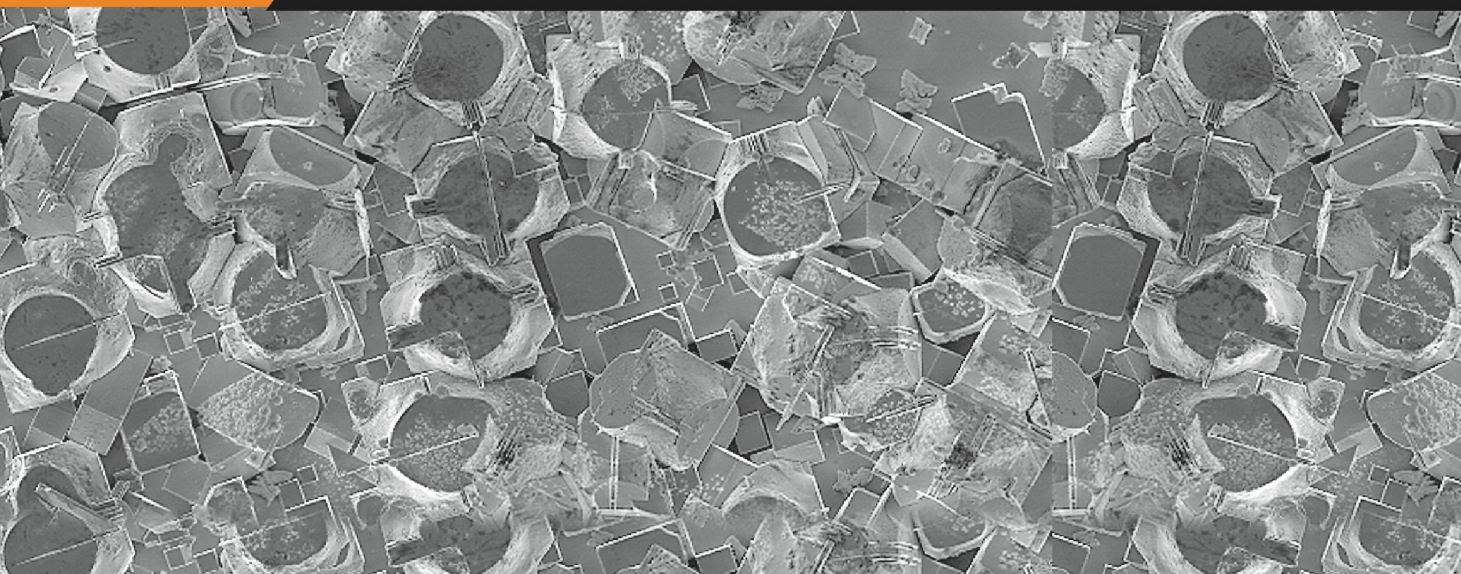
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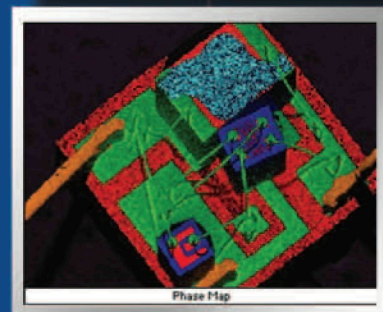
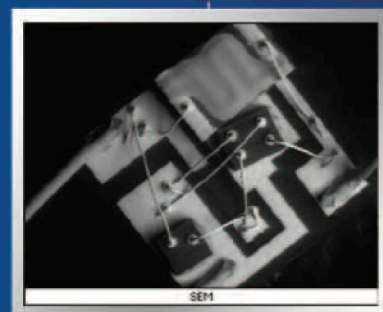
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